

High-Resolution Low-Sampling-Rate $\Delta\Sigma$ ADC Linearity Short-Time Test Algorithm

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OUTLINE

- Research background and objective
- Proposed linearity test method
- Simulation configuration and results
- Conclusion

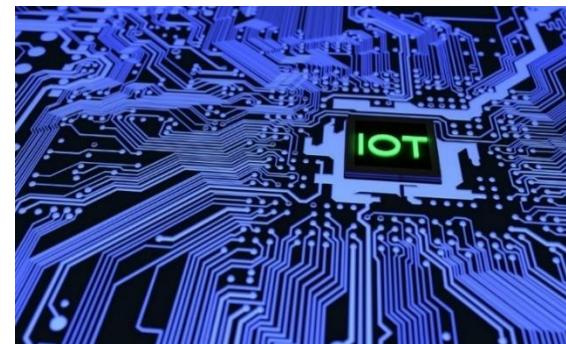
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Research Background

IOT(Internet of things)

- Testing and evaluation of IOT devices are becoming important.



- Mass production shipment of IOT devices requires high quality and low cost testing.

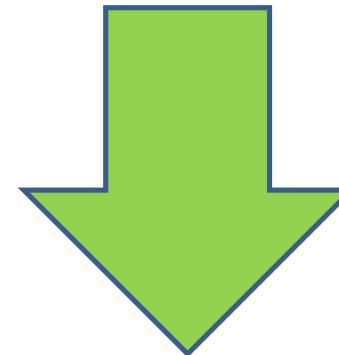


Research Objective

High resolution, low speed $\Delta\Sigma$ ADC

- Sensor interface key components
- Mass production test
 - ✓ Linearity test takes a long time.
 - ✓ In most cases, it is omitted.

High reliability requirements



- ✓ Perform its linearity test in a short time
- ✓ Develop its algorithm

$\Delta\Sigma$ ADC Testing Challenge

Sensor + amplifier + $\Delta\Sigma$ ADC + microcomputer



4 difficulties for its mass production shipping test.

- ① Low speed sampling
- ② High resolution



Long test time

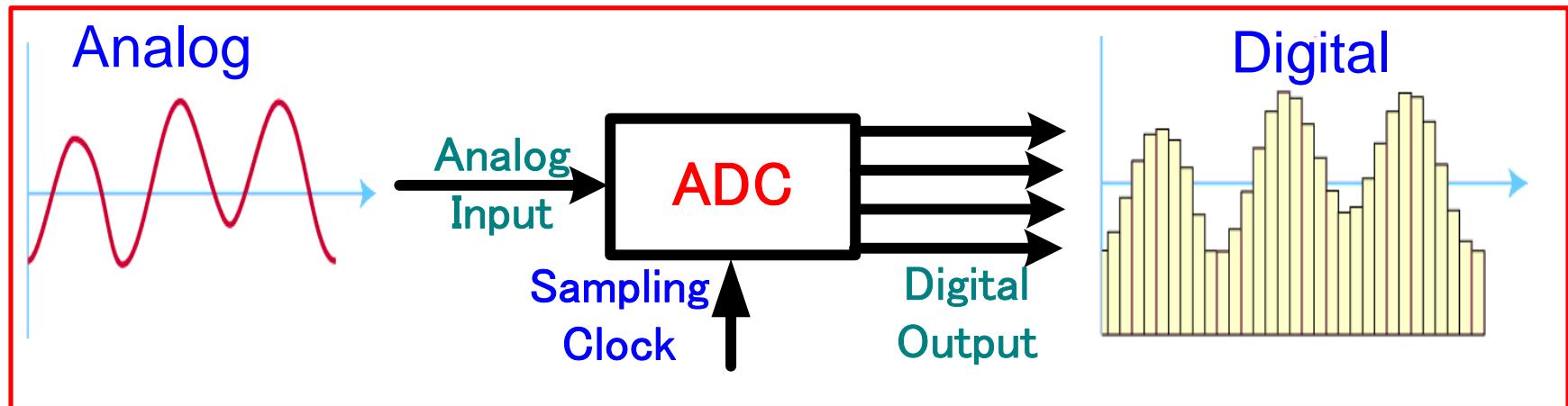
- ③ High linearity analog input signal
- ④ Complex ADC output signal processing

1 US dollar chip



Test time should be less than 1 second

ADC Role in Digital Era

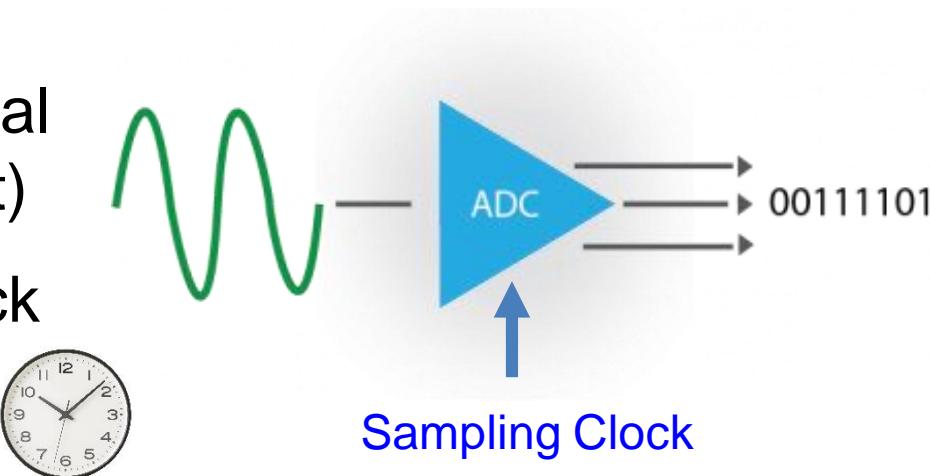


Analog signal :
continuous signal



Digital signal :
discrete numerical signal

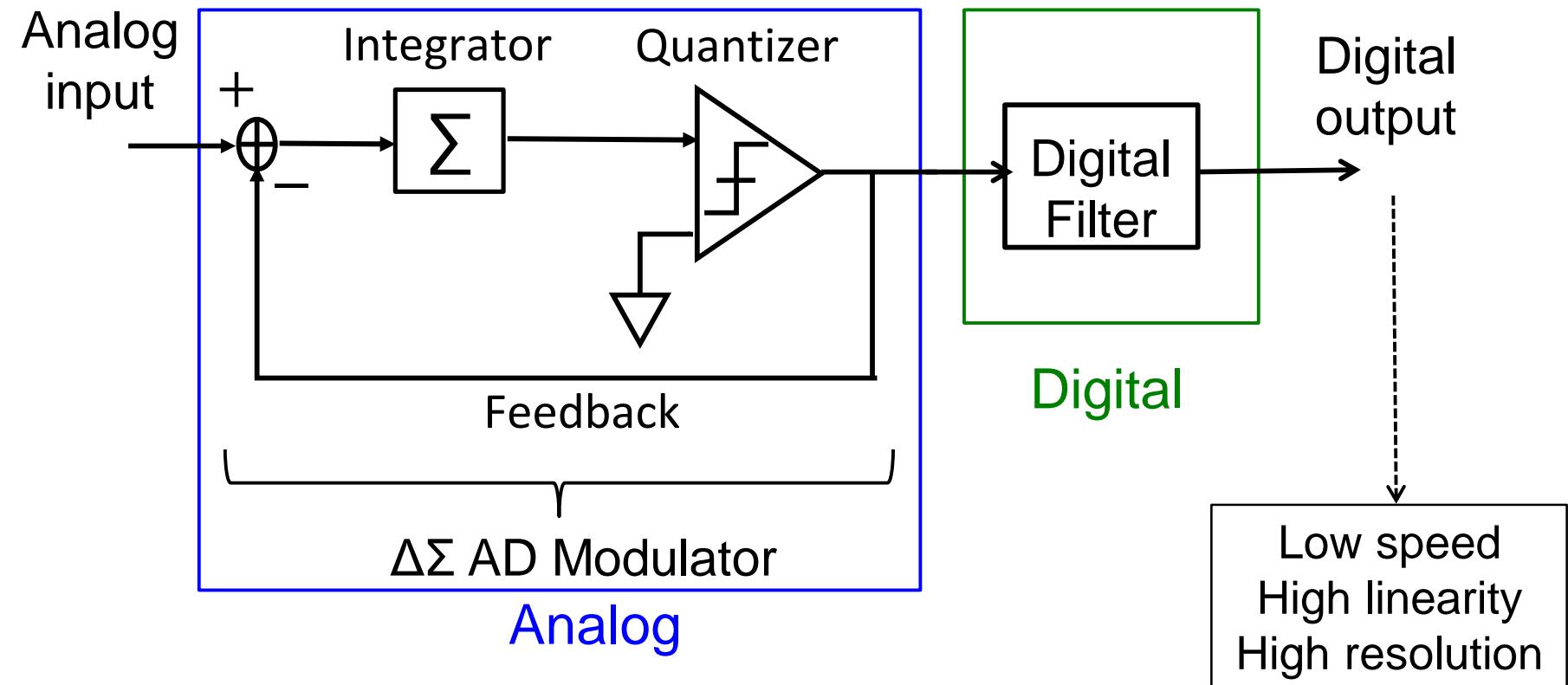
- ◆ Natural signal
(sound, light)
- ◆ Analog clock



- ◆ Binary number
- ◆ Digital clock

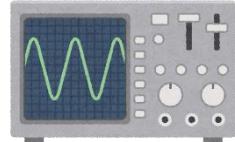


$\Delta\Sigma$ ADC



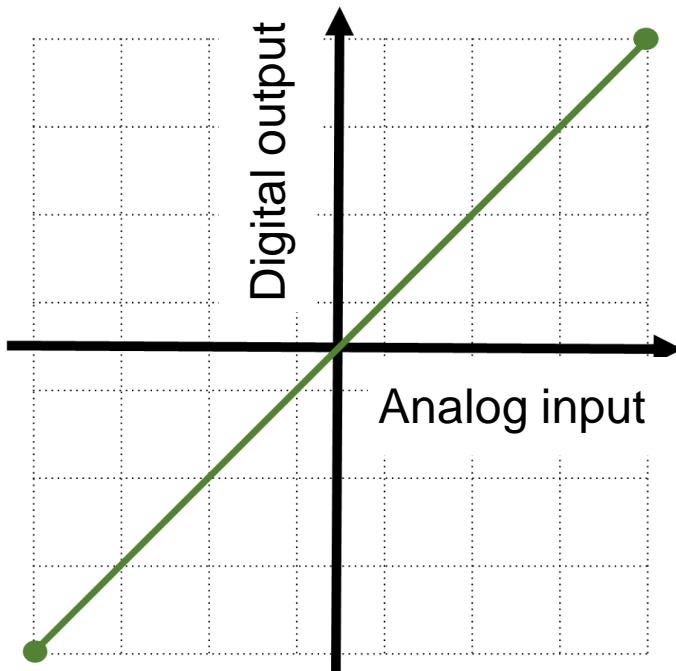
<Application>

- Measurement
- Audio system
- Satellite communication

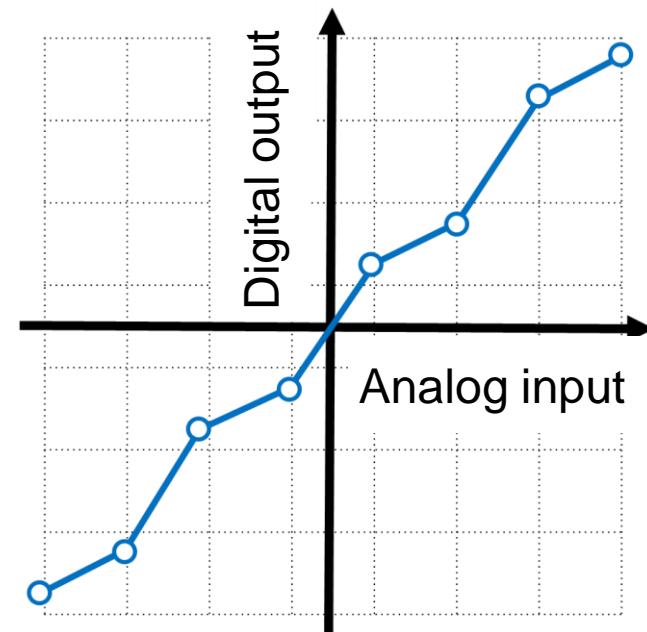


Linearity of $\Delta\Sigma$ ADC

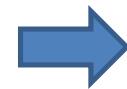
Ideal characteristic (linear)



Actual (nonlinear)



Circuit imperfection, variation



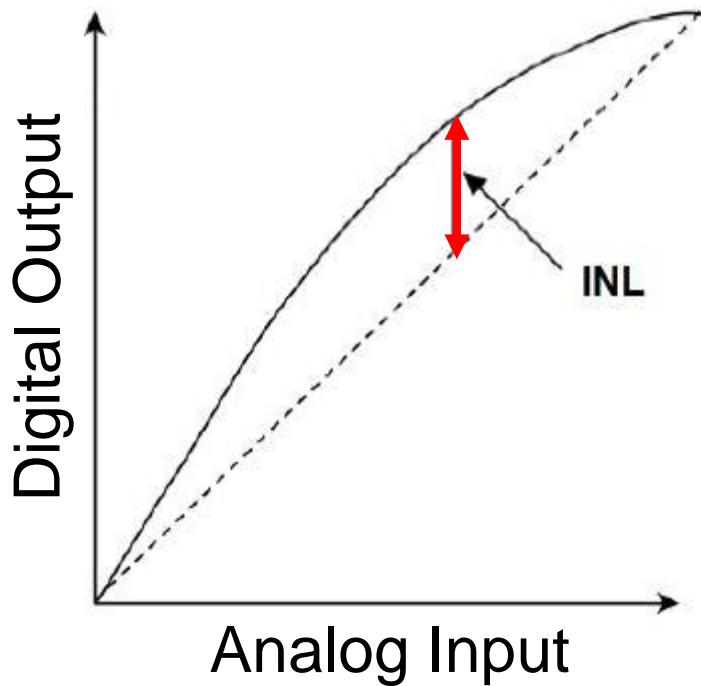
Nonlinear



Linearity :

- ✓ Important performance item
- ✓ Need its accurate test in a short time.

Integral Non-Linearity: INL



If INL is large :

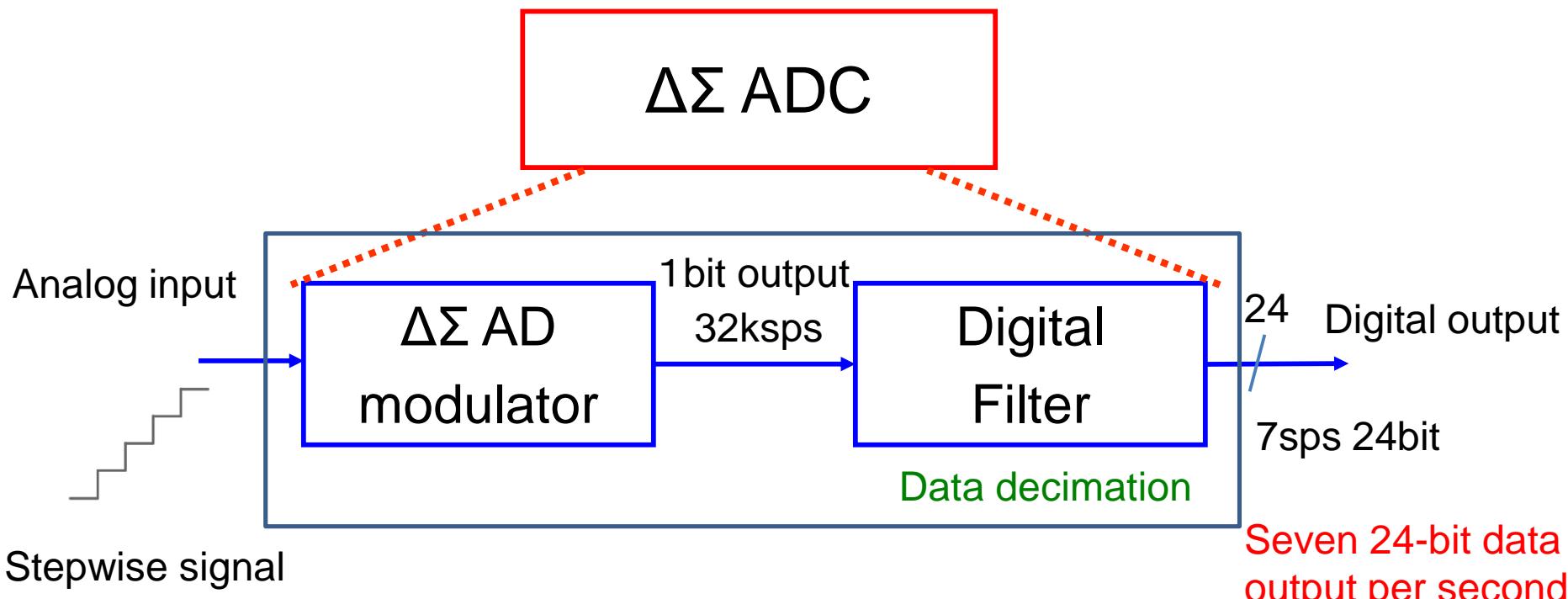
- ✓ Missing codes occur
- ✓ Lack of monotonicity

Deviation between the ideal input threshold value and the measured threshold level of a certain output code.

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Problem of Direct Linearity Test



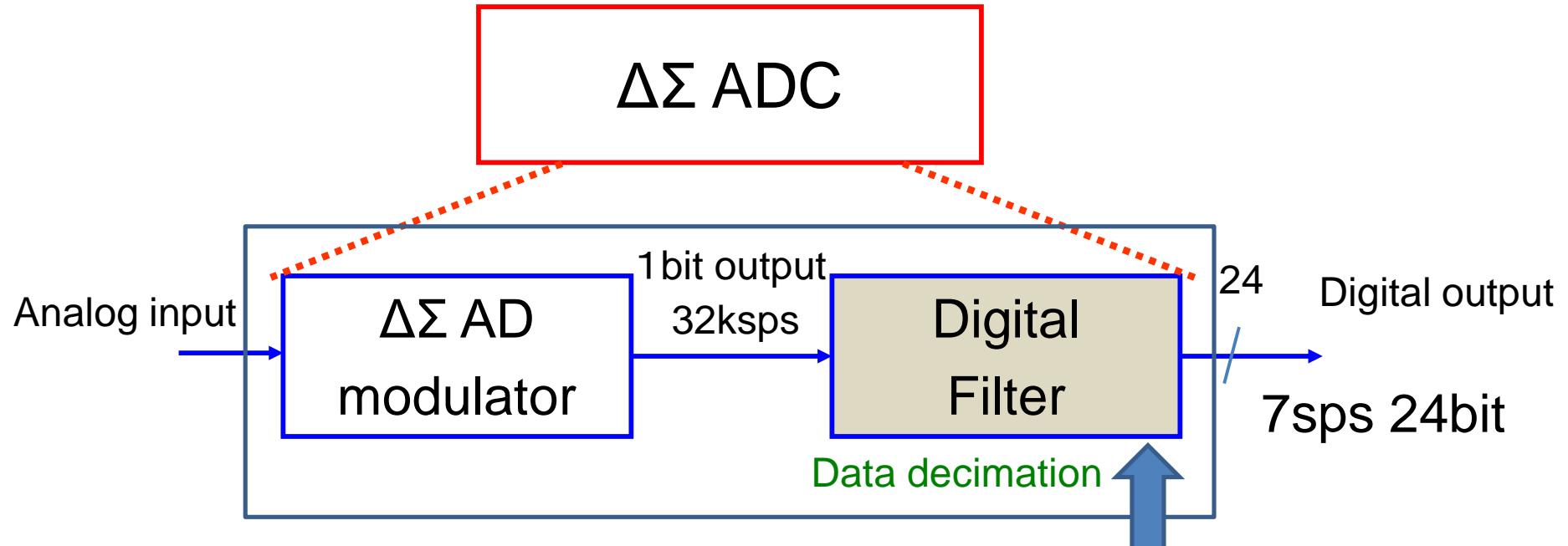
Linearity test time

Assuming 4 point per code
 $(1/7) \times 2^{24} \times 4$ seconds = 104 day !



Totally unrealistic

Digital Filter Test



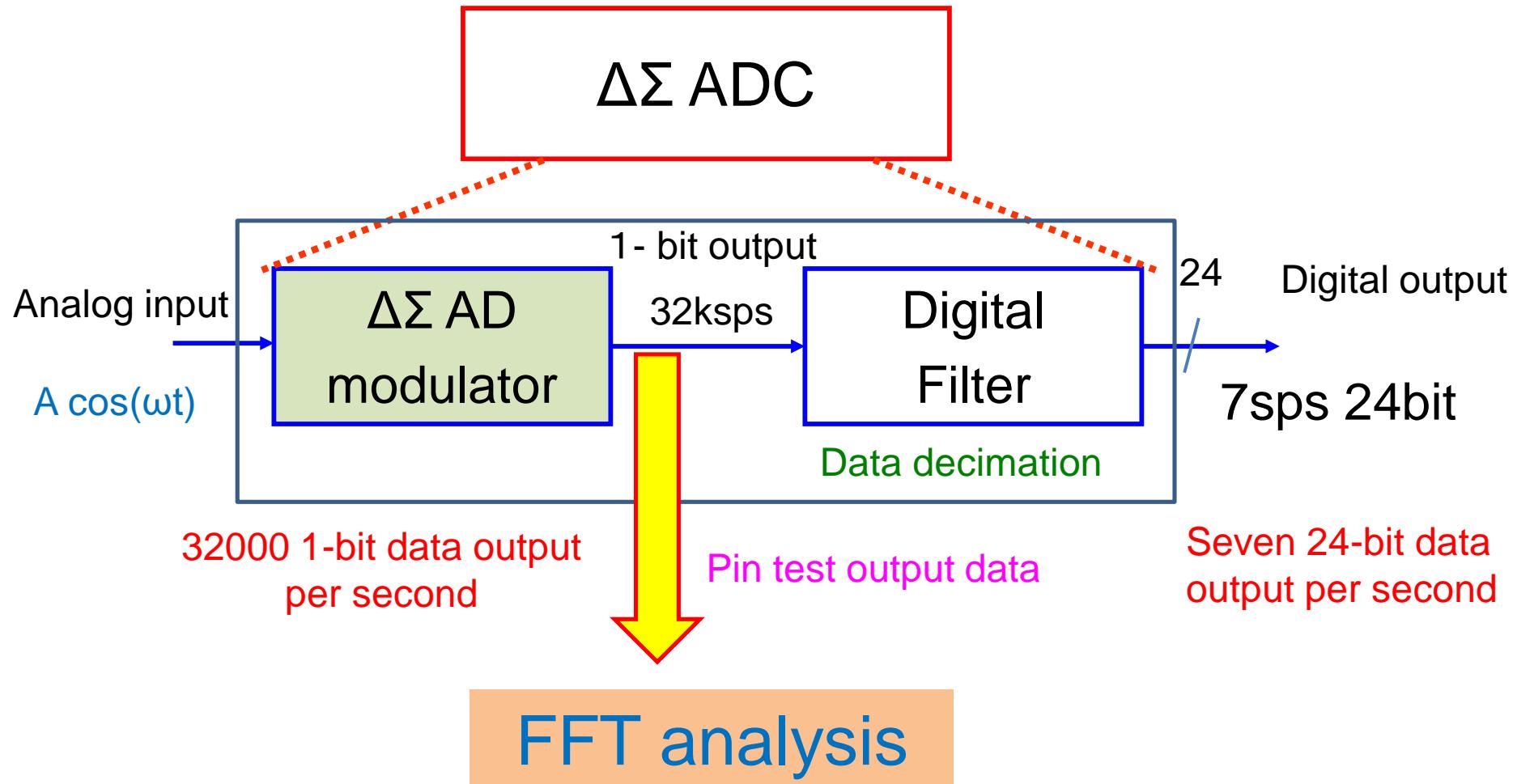
Digital filter does NOT affect the linearity.

Only pass or fail.

**Test with
scan path method**

$\Delta\Sigma$ AD Modulator Test

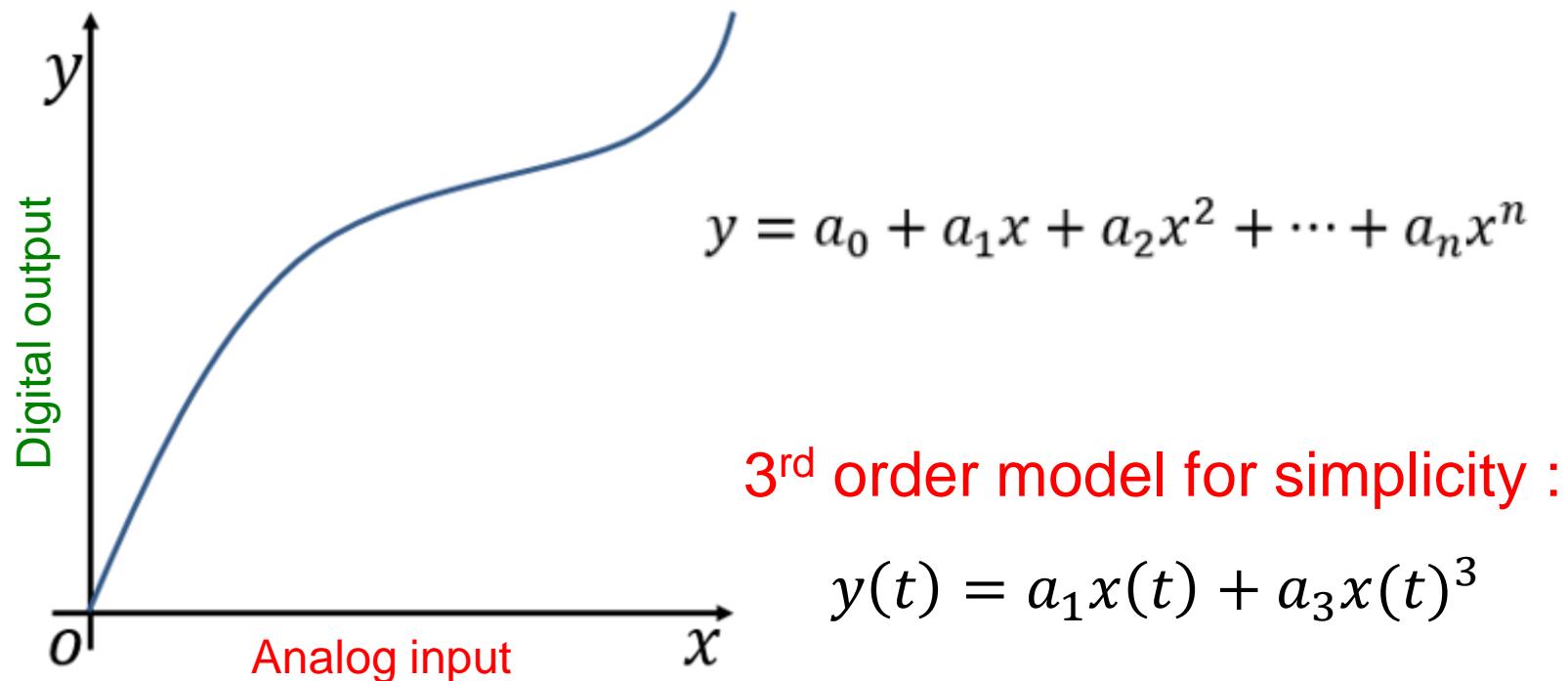
Proposed: Cosine Input & FFT Analysis



I/O Characteristic Modeling of Modulator

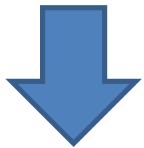
Modeling by polynomial approximation

- ✓ Assumption: I/O characteristics are continuous in the AD modulator.



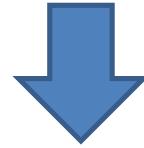
Polynomial Coefficient Estimation

Analog cosine input :
 $x(t) = A \cos(\omega t)$

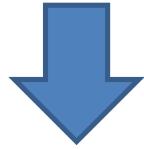


Modulator 1-bit output stream

FFT

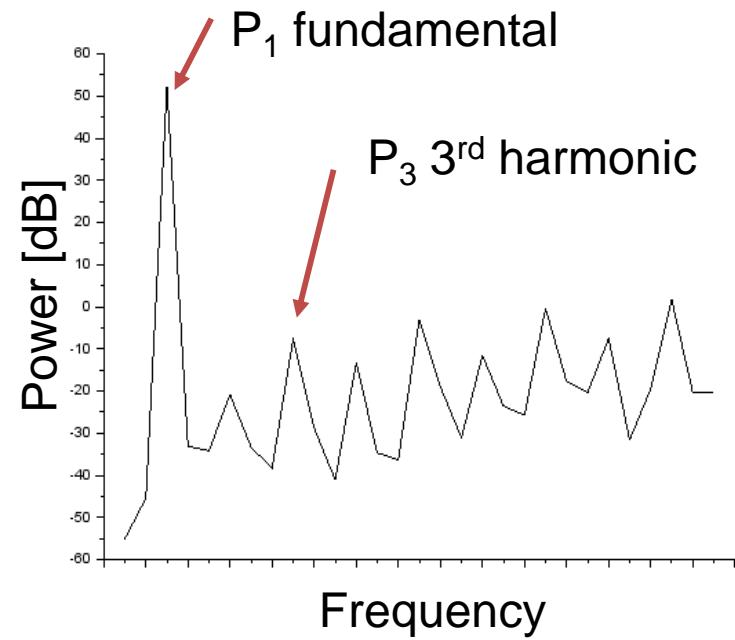


Measure fundamental &
 3^{rd} harmonic power



Estimate a_1, a_3 :
 $y(t) = a_1 x(t) + a_3 x(t)^3$

Proposed algorithm



Fundamental / 3rd Harmonic Power and Polynomial Coefficients

Cosine input :

$$x(t) = A \cos \omega t$$

Output characteristic model :

$$y(t) = a_1 x(t) + a_3 x(t)^3$$

$$y(t) = a_1 A \cos \omega t + a_3 (A \cos \omega t)^3$$



$$(a_1 A + \frac{3}{4} a_3 A^3) \cos \omega t + \frac{1}{4} a_3 A^3 \cos 3\omega t$$



Fundamental

$$a_1 A + \frac{3}{4} a_3 A^3$$



3rd harmonic

$$\frac{1}{4} a_3 A^3$$

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Simulation Verification of Proposed Algorithm

Proposed $\Delta\Sigma$ ADC linearity test method

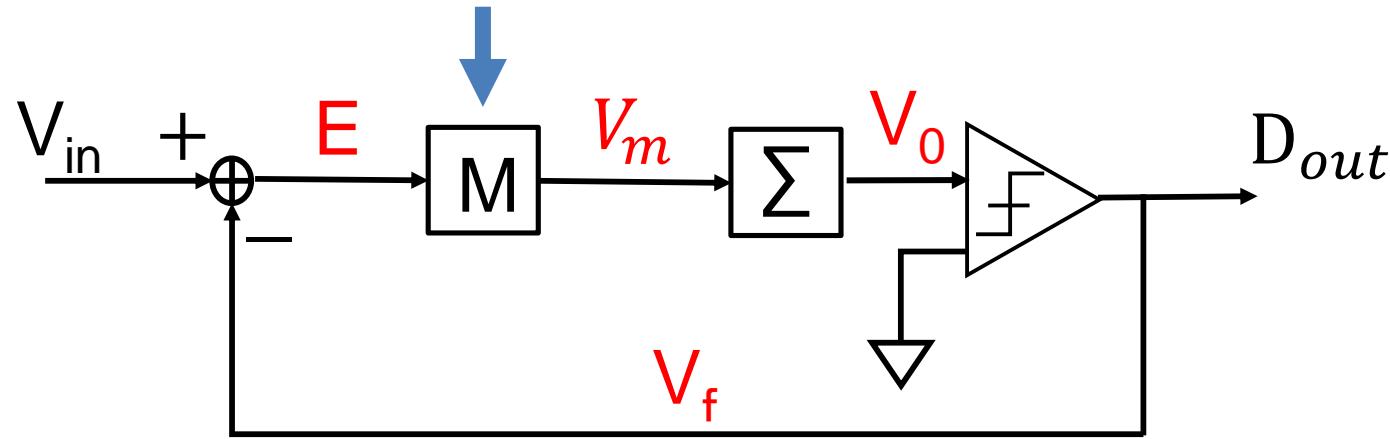


- Highly accurate estimation of polynomial coefficients from FFT values
 - Modulator 1 bit data output of 2^{20}
 $2^{20} / (32 \times 1000) = 32$ seconds
-
- A large green arrow pointing downwards, indicating a flow or consequence from the method to its results.
- Test time drastically reduced
 - 32 pieces are tested in parallel simultaneously, equivalent testing time per unit is 1 second .

1st-order Modulator, 3rd-order Nonlinearity Model

3rd-order nonlinearity model

$$V_m = E - k * E^3 \quad (k > 0)$$



1st-order modulator

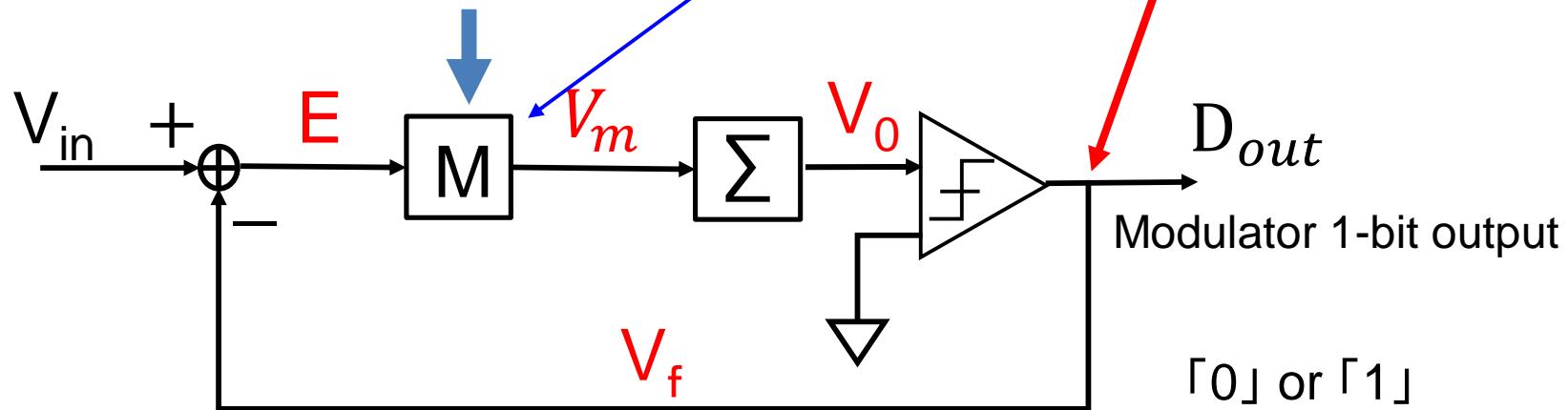
DC Input Simulation

- ◆ Number of data : $N=2^{20}$
- ◆ V_{in} : DC = -1.0 ~ +1.0
- ◆ $k = 0.0001, 0.0005, 0.001,$
 $0.005, 0.01$



$$V_m = E - k * E^3 \quad (k > 0)$$

Control by the number of 1's

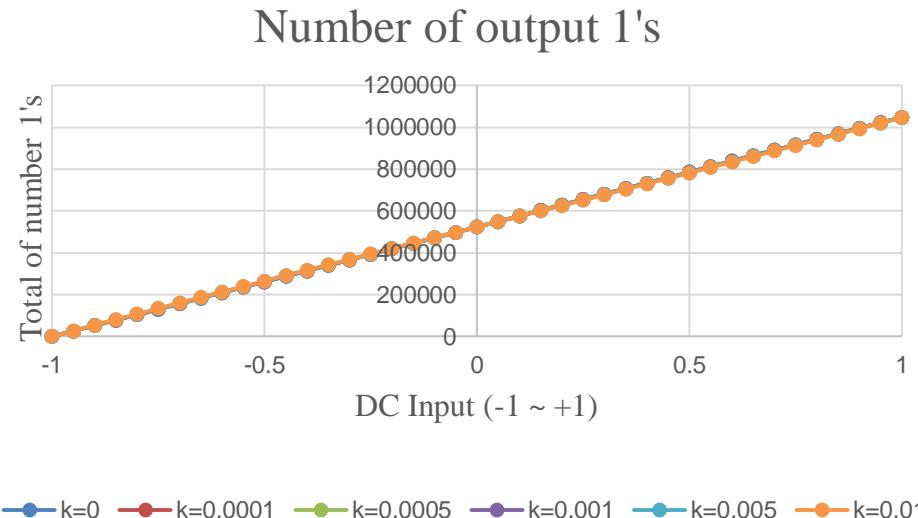


1st -order modulator

DC Input Simulation Result

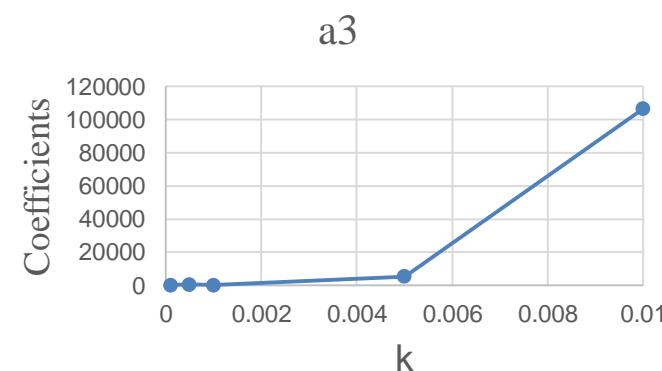
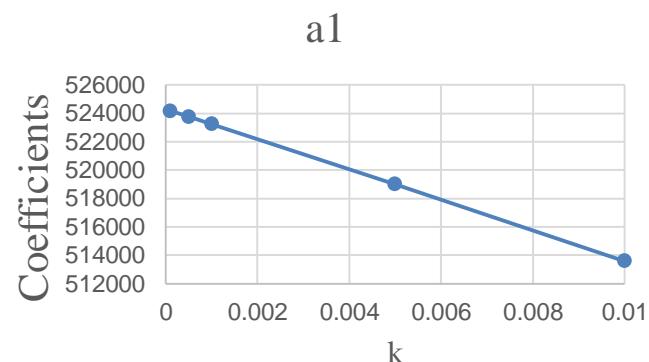
Number of modulator output:
 $N=2^{20}$

DC characteristic curve fitting



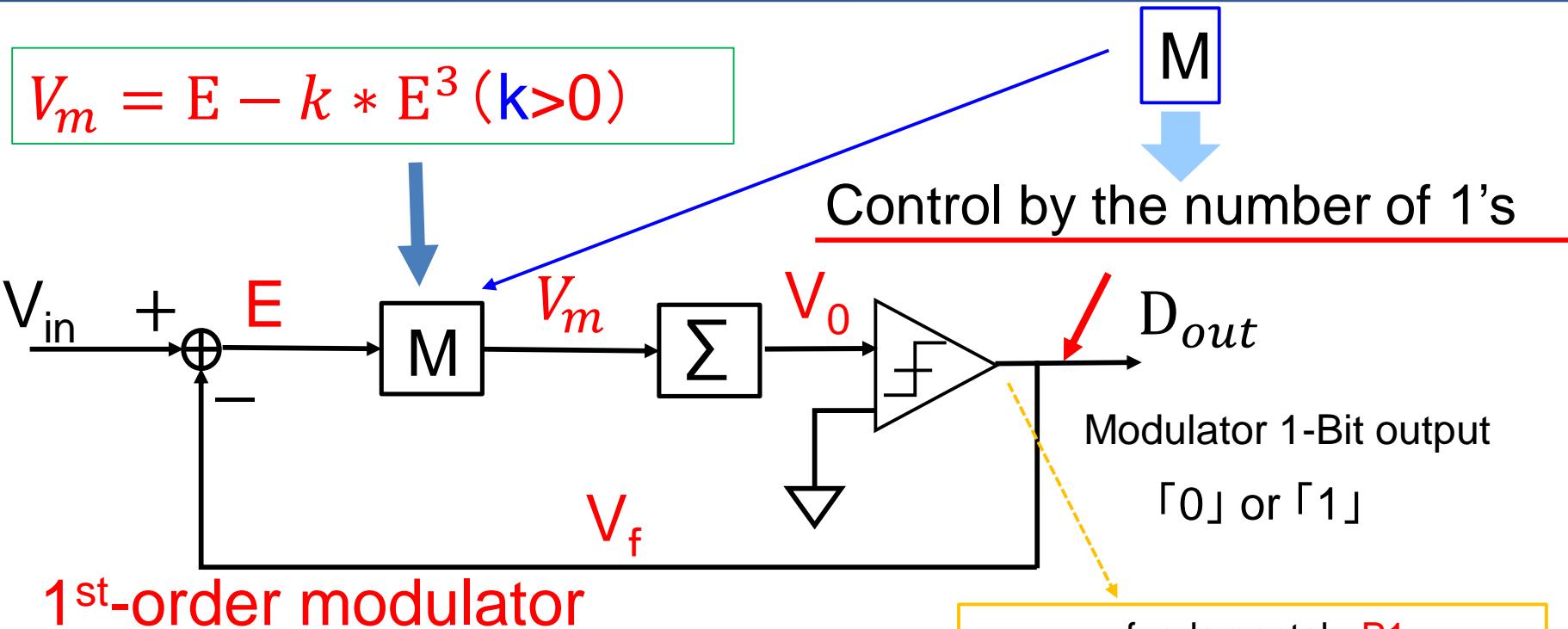
\downarrow

$$y = a_3 \cdot x^3 + a_1 \cdot x$$



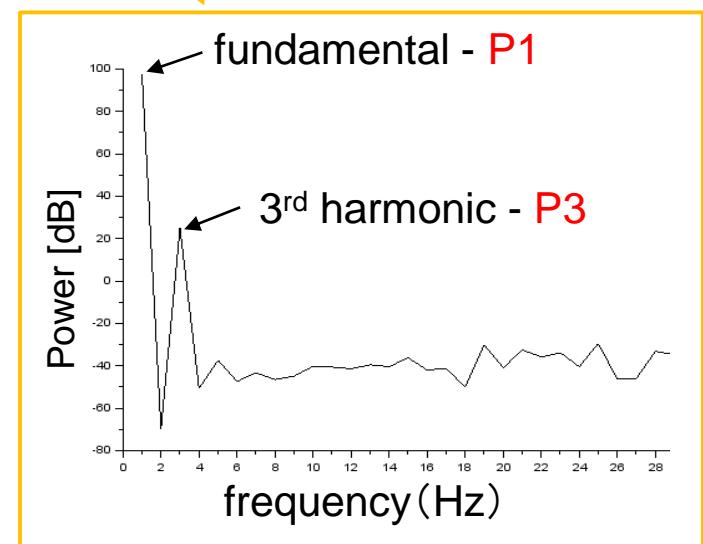
k	a_3	a_1
0.0001	104.84	524180
0.0005	524.48	523760
0.0010	1050.5	523240
0.0050	5282.5	519000
0.0100	10643.0	513610

Cosine Input Simulation Configuration

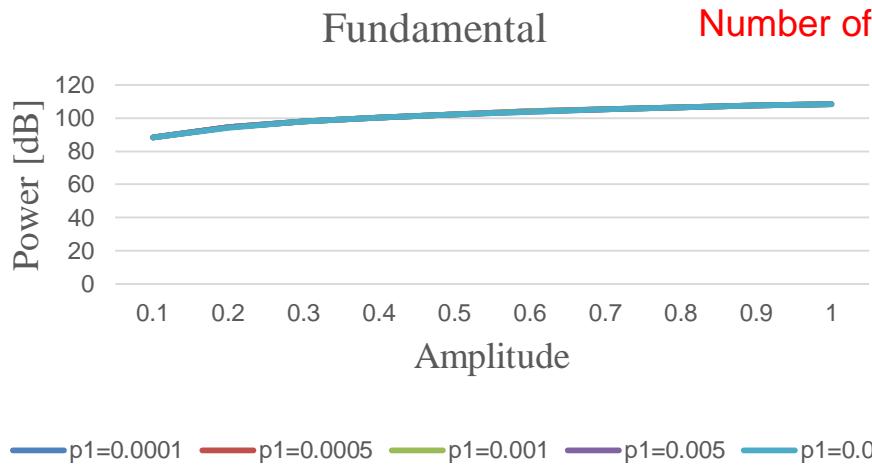


- ◆ Number of data : $N=2^{20}$
- ◆ V_{in} : $\text{Acos}(\omega t)$ ($A = 0.1 \sim 1$)
- ◆ $k=0.0001, 0.0005, 0.001,$
 $0.005, 0.01$

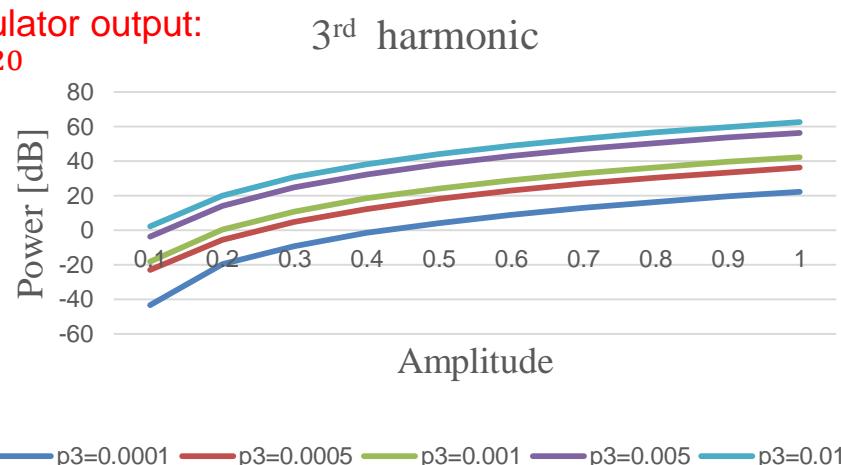
2019/11/8



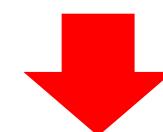
Cosine Input Simulation Result



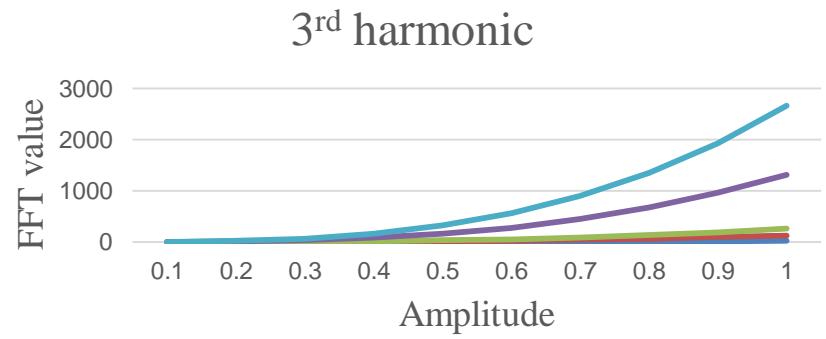
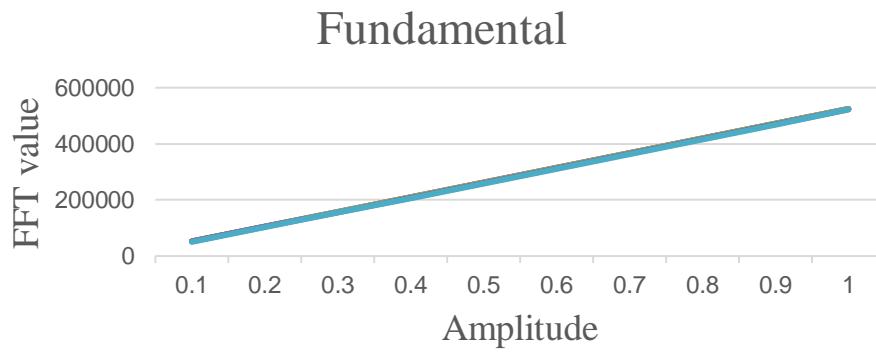
Number of modulator output:
 $N=2^{20}$



Power = $20\log(\text{FFT}_{\text{value}}) - 6.02$ [dB]



FFT result



— Q1=0.0001 — Q1=0.0005 — Q1=0.001 — Q1=0.005 — Q1=0.01

— p3=0.0001 — p3=0.0005 — p3=0.001 — p3=0.005 — p3=0.01

Find Spectrum Power from DC Characteristics

- ◆ 1st - order modulator
- ◆ Number of 1-bit output data : $N=2^{20}$

By nonlinearity

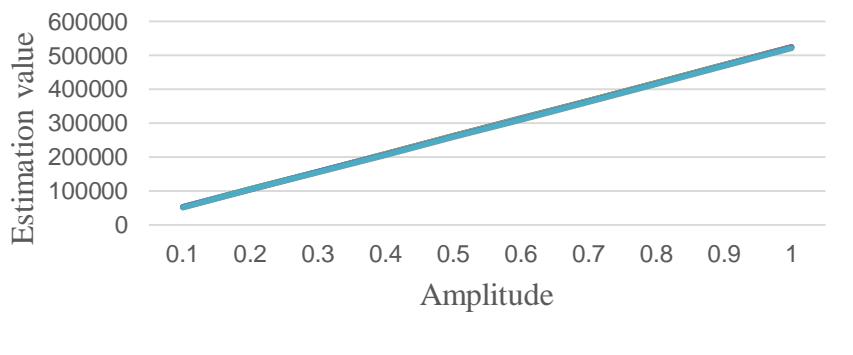
Fundamental : $a_1 A + \frac{3}{4} a_3 A^3$

3rd harmonic : $\frac{1}{4} a_3 A^3$

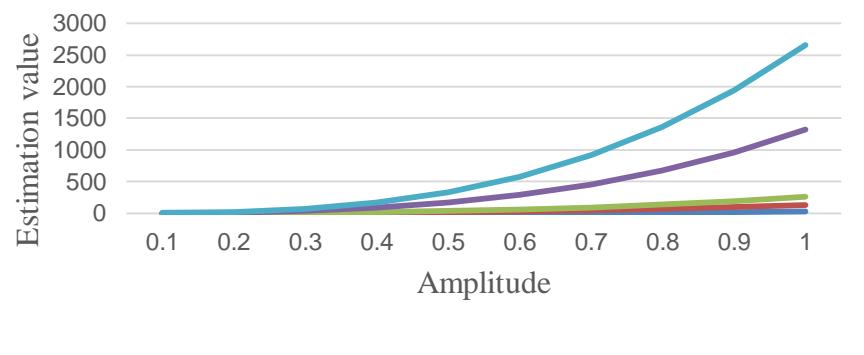
A:amplitude

k	a_3	a_1
0.0001	104.84	524180
0.0005	524.48	523760
0.0010	1050.5	523240
0.0050	5282.5	519000
0.0100	10643.0	513610

Fundamental estimation value

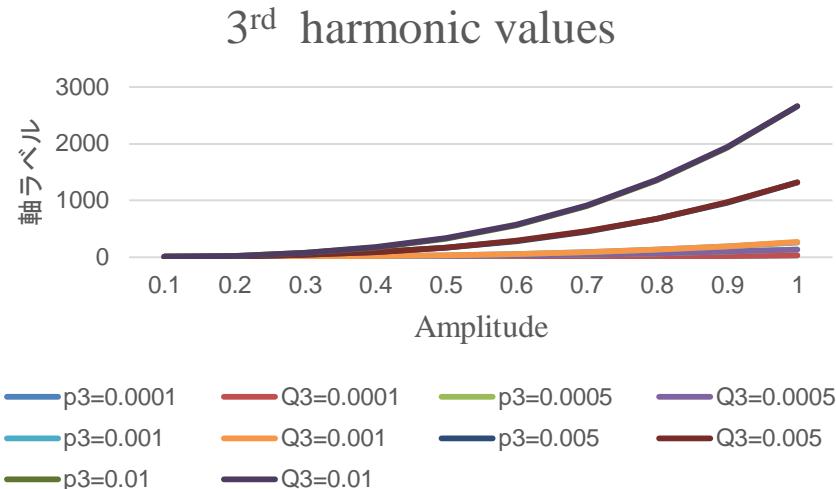
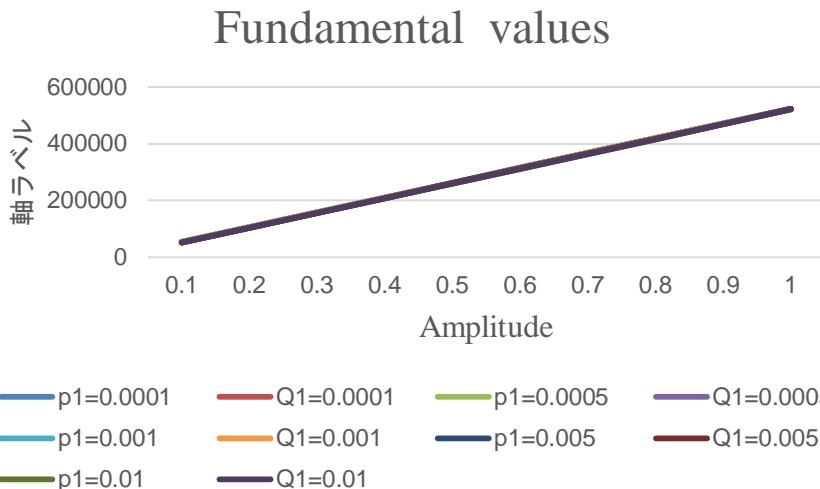


3rd harmonic estimation value



N=2²⁰

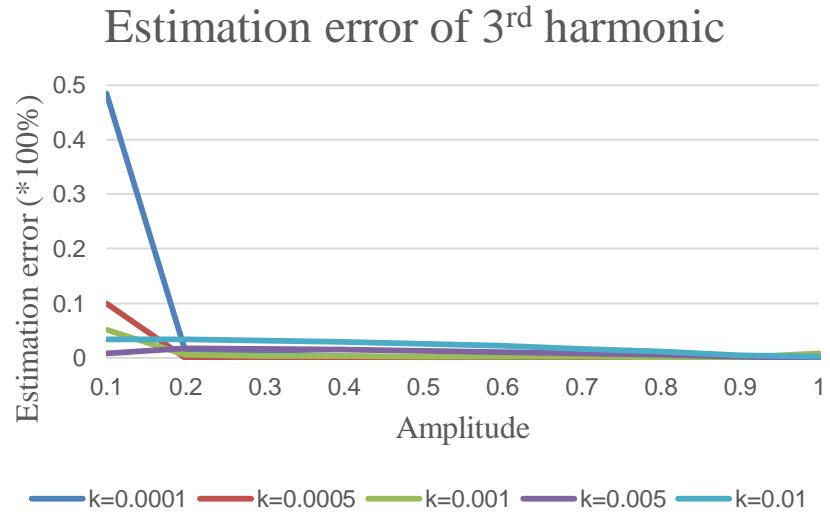
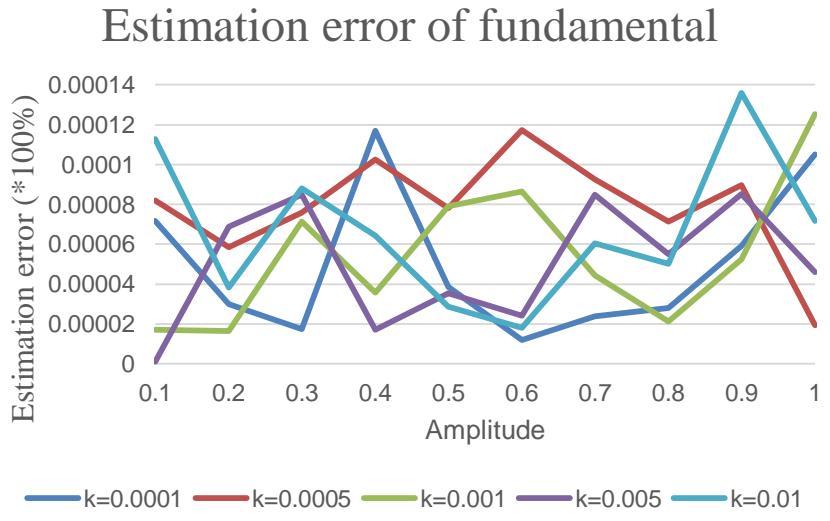
Comparison Between Estimated and FFT Values



P₁ : fundamental obtained by FFT
 Q₁ : estimated fundamental

$$\text{Error} = \frac{Q_{\text{values}} - P_{\text{values}}}{Q_{\text{values}}}$$

P₃ : 3rd harmonic obtained by FFT
 Q₃ : estimated 3rd harmonic



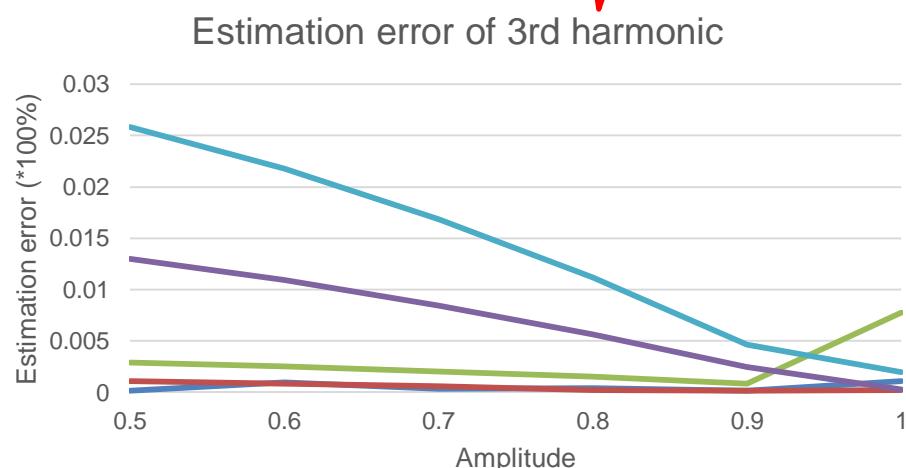
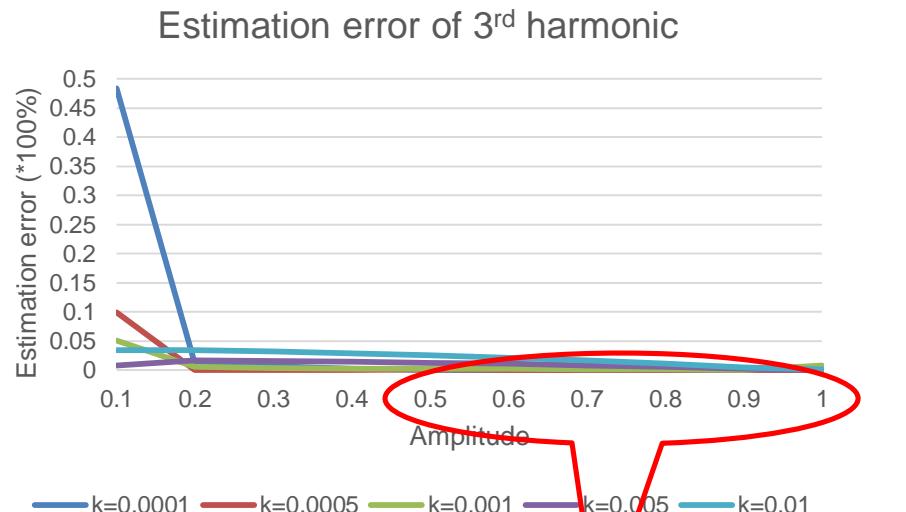
N=2²⁰

Accurate Estimation Condition for 3rd Harmonic

1st -order modulator

Good condition
3rd harmonic

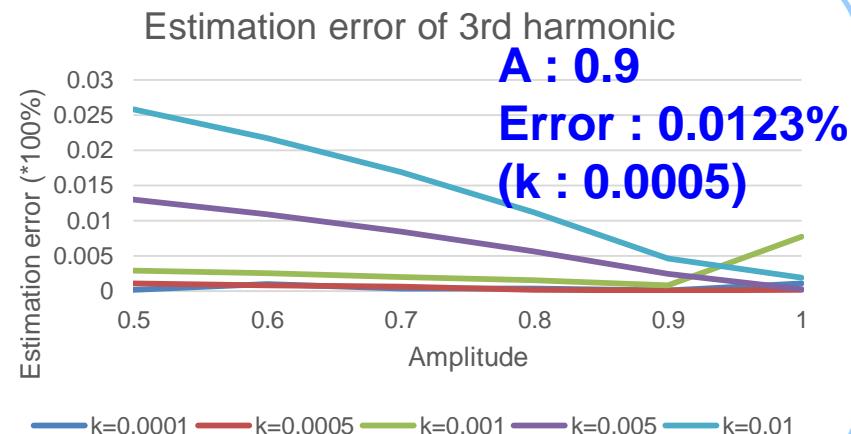
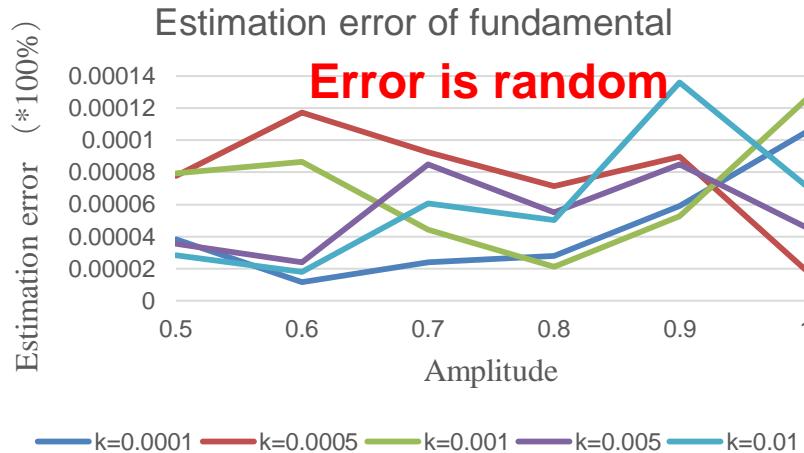
Amplitude = 0.9
Error = 0.0123%
(k = 0.0005)



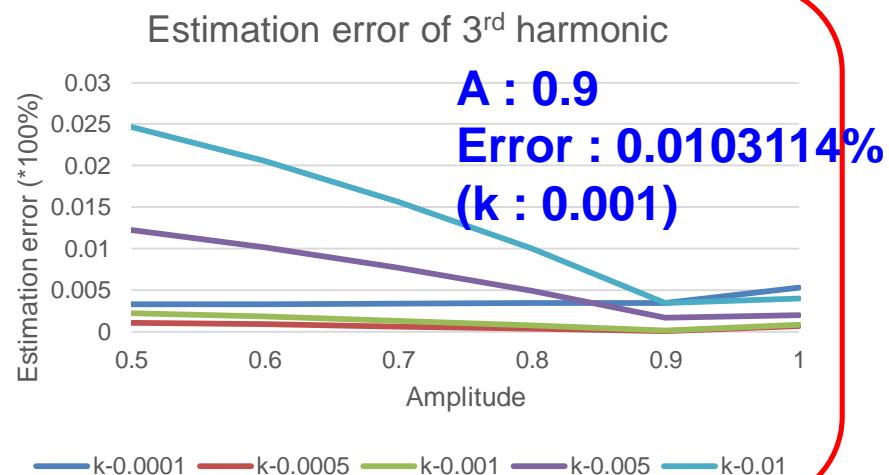
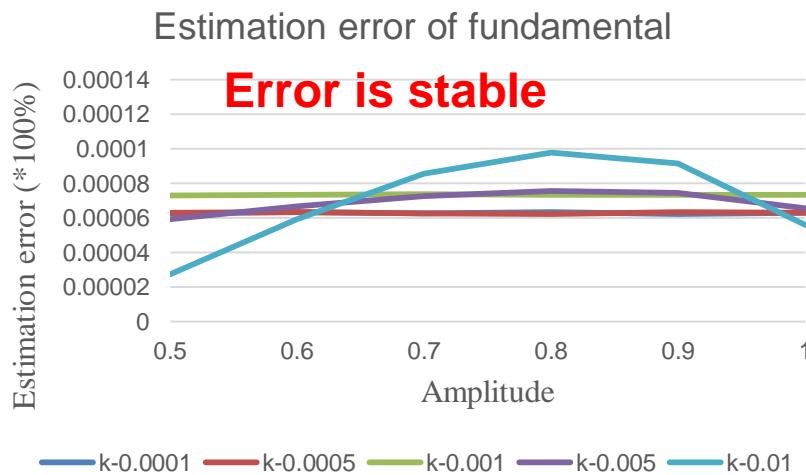
N=2²⁰

Comparison of 1st and 2nd -order Modulators

1st -order modulator

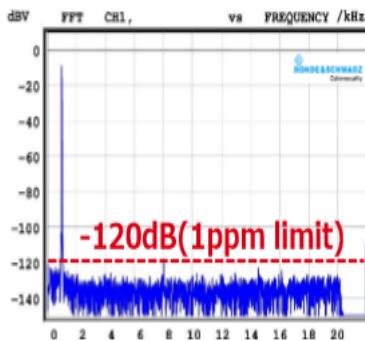


2nd -order modulator



DUT Measurement Result

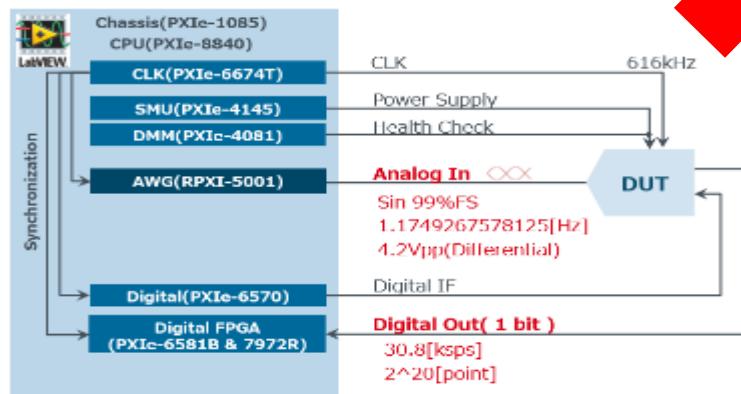
➤ Measurements results from Rohm semiconductor company



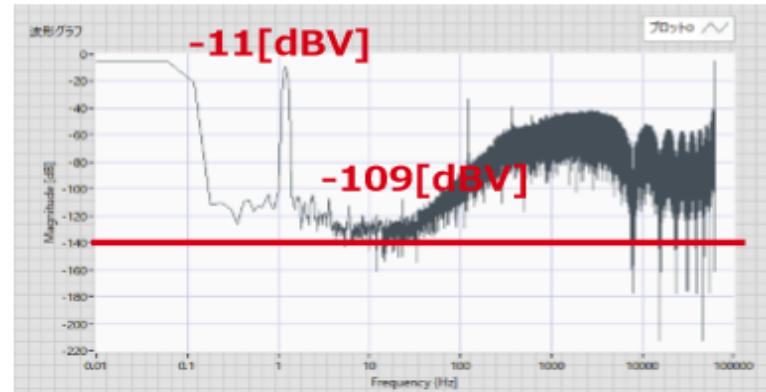
Output : 1kHz 44.1ksps
 THD : 122dB(~Fifth Harmonics)
 SN : 132dB(Filter:20kHzLPF)

Meet the requirements
 Signal from our developed AWG
 (AWG: Arbitrary Waveform Generator)

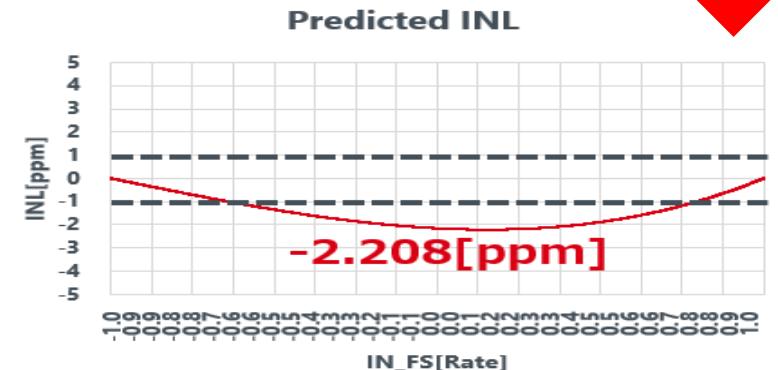
Test System Diagram and Test Condition



Use of NI PXI system
for experiment



Experimental result of
the modulator output FFT



Obtained INL prediction
with the proposed method

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Conclusion

- High resolution, low speed $\Delta\Sigma$ ADC linearity short time testing algorithm
 - ✓ Polynomial modeling of modulator input / output characteristics
 - ✓ FFT of modulator 1-bit output stream for cosine input
 - ✓ Estimate polynomial coefficients from fundamental and harmonic powers
- Verified by simulation and experiments that the proposed method is feasible.

Drastic testing time reduction:

104 days  32 seconds

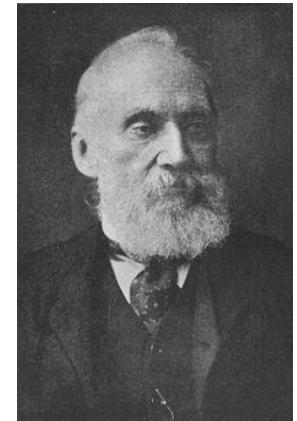
Future Work

Consideration of the followings:

- Higher-order distortions
 - High-order polynomial modeling
- Application to high-order modulators
- Application to multi-bit modulators

Final Statement

No Science without Measurement

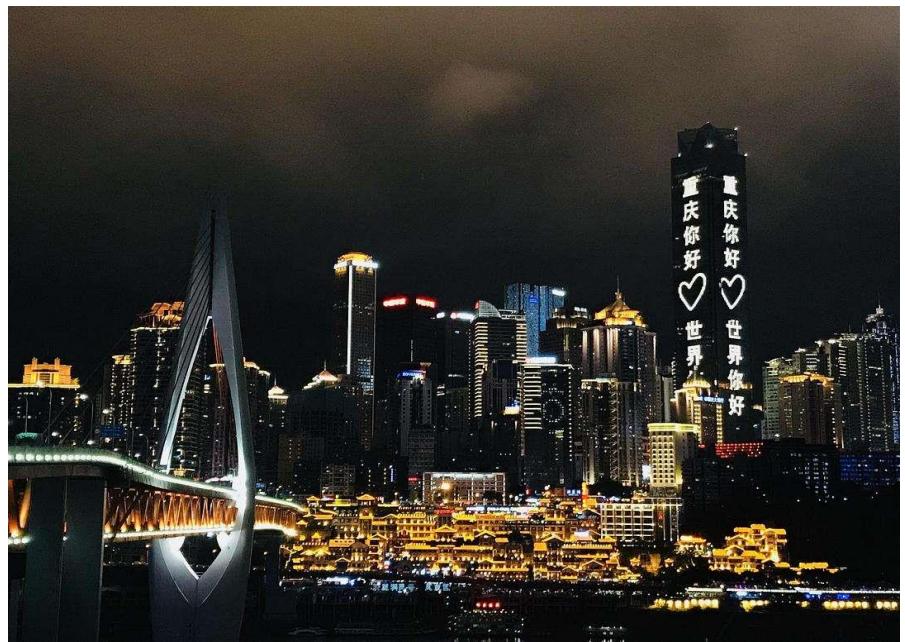


Lord Kelvin

Kelvin PNP

No Production without Testing

Thanks for listening!



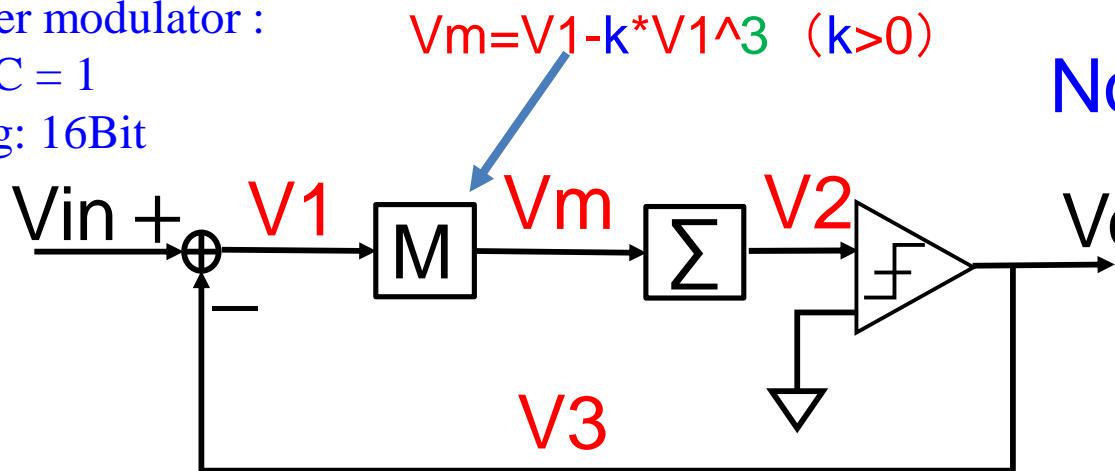
Appendix

DC Input Amplitude

First order modulator :

Input: DC = 1

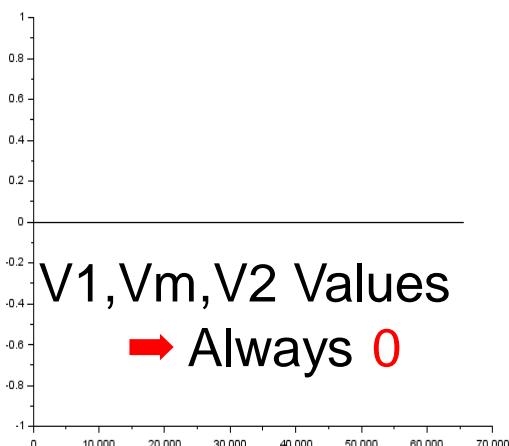
Sampling: 16Bit



$$V1(i) = V_{in}(i) - V3(i)$$

$$Vm(i) = V1(i) - k * V1(i)^3 \quad (K > 0)$$

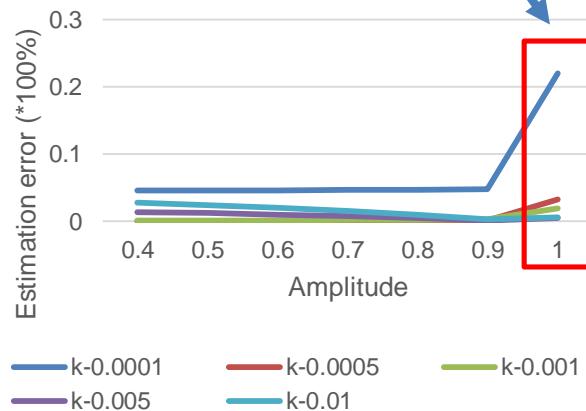
$$V2(i) = V2(i-1) + Vm(i)$$



V3 value
→ Always 1

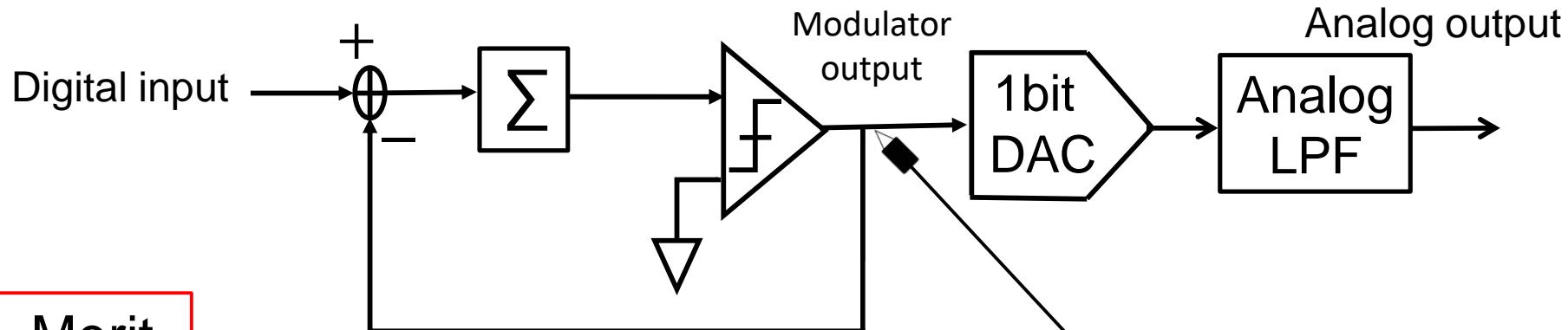
Nonlinearity Model

If A=1
Estimation error
become bigger



So, A=1.
→ It can't be modulator.

Merits & Demerits of $\Delta\Sigma$ DAC



Merit

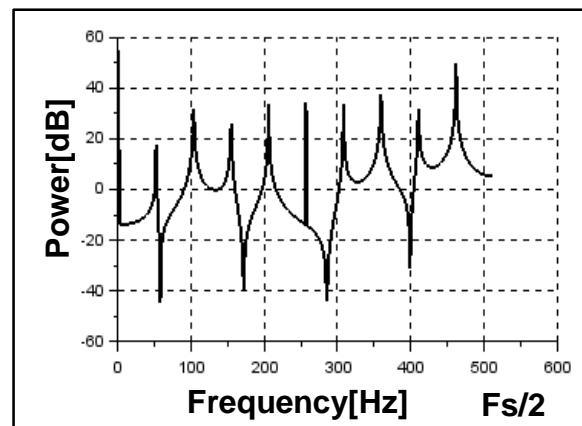
- Mostly digital circuit
- High linear & high resolution for low frequency signal generation

Demerit

- Limit cycle problem for small input

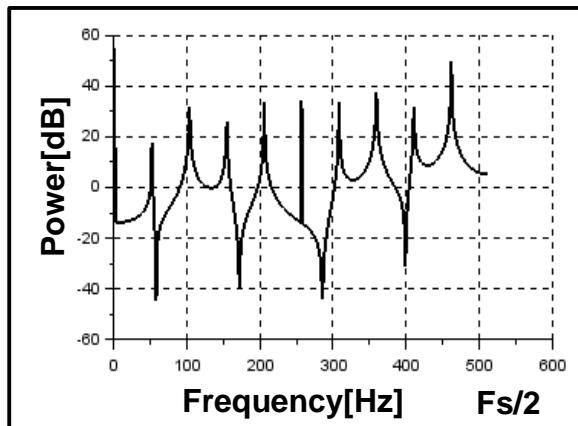
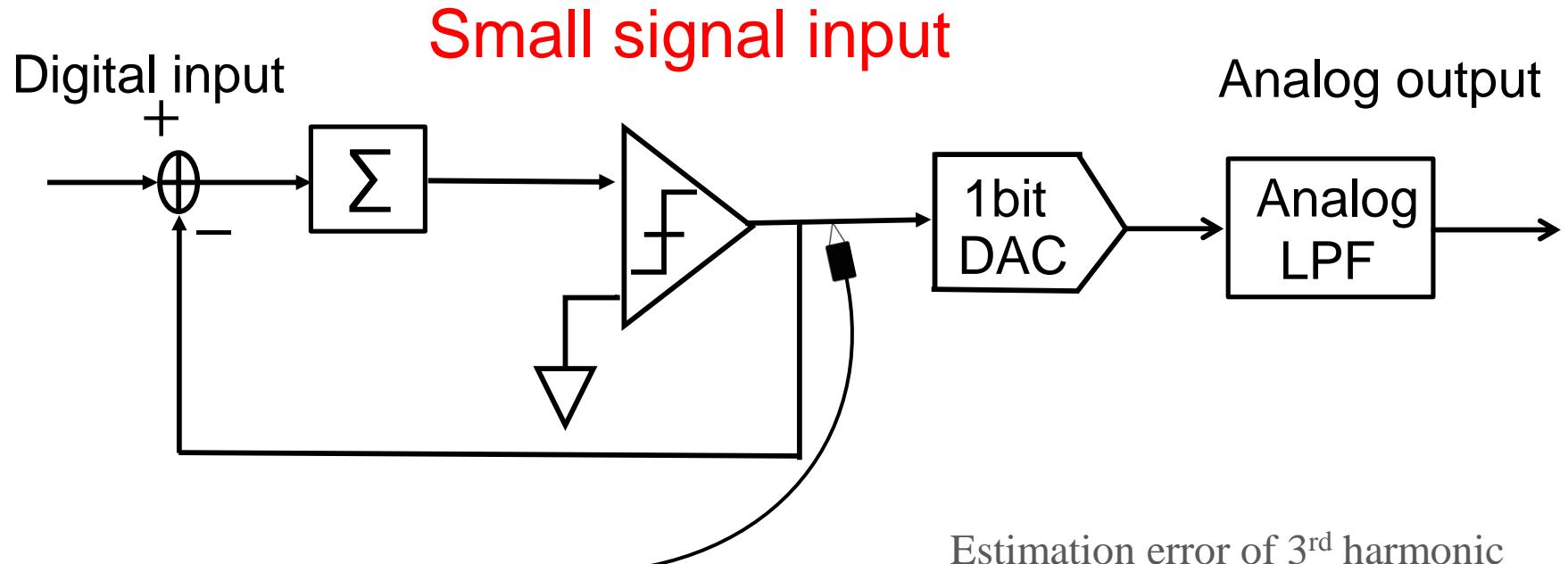


Limit cycle

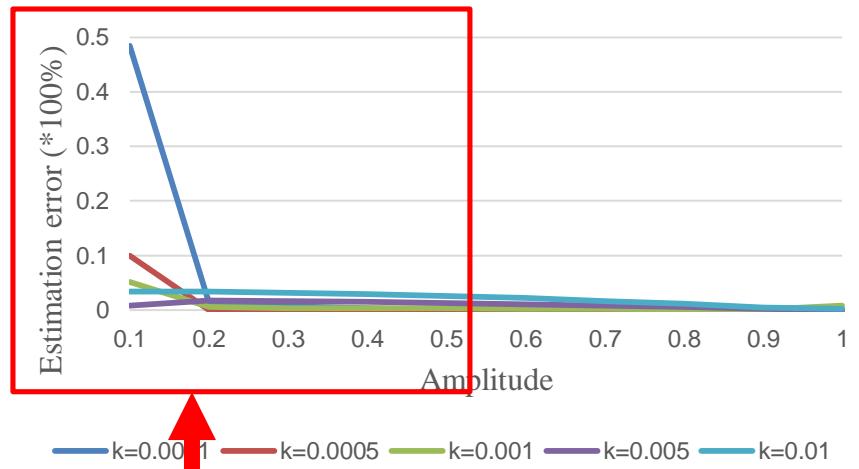


✖ Due to modulator nonlinearity by quantizer

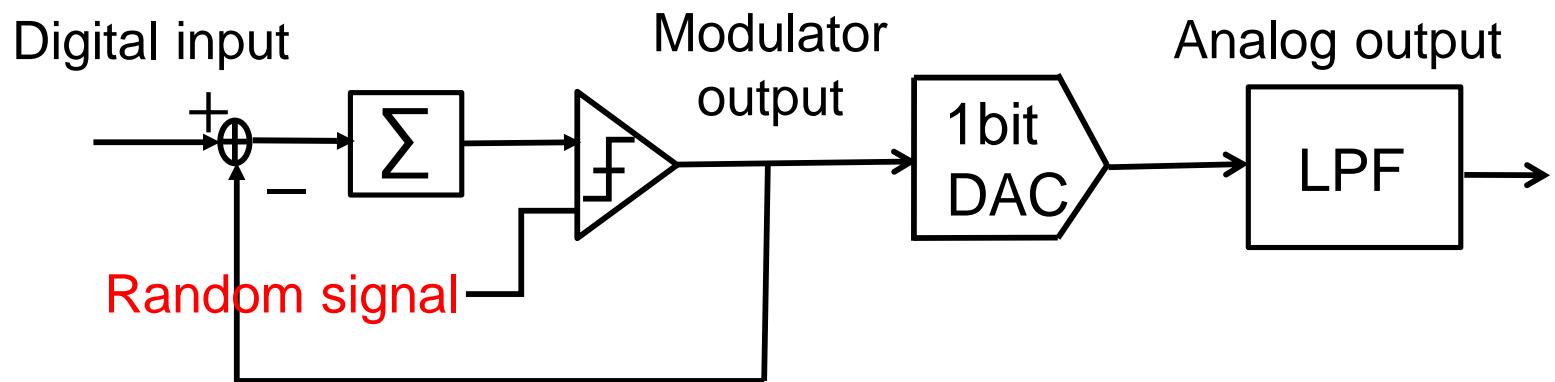
DC small signal input



Estimation error of 3rd harmonic



Limit cycle solution



< Features >

- ① NOT sacrifice input range
- ② NOT affect signal band, thanks to noise-shaping
- ③ Easily generate random signal.

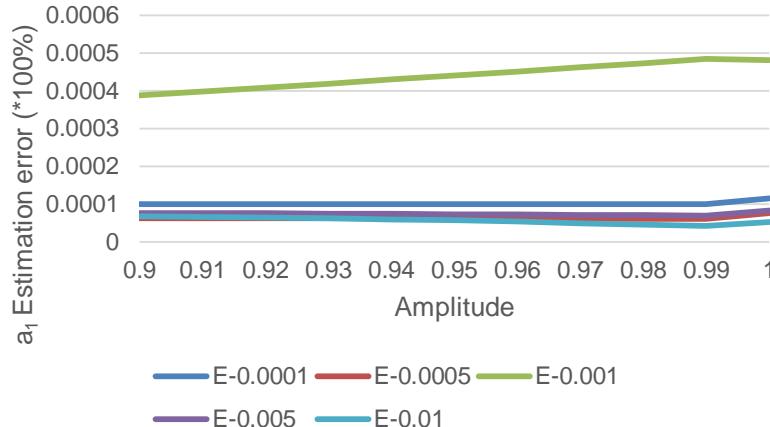
First-order modulator (3rd nonlinearity)

fundamental

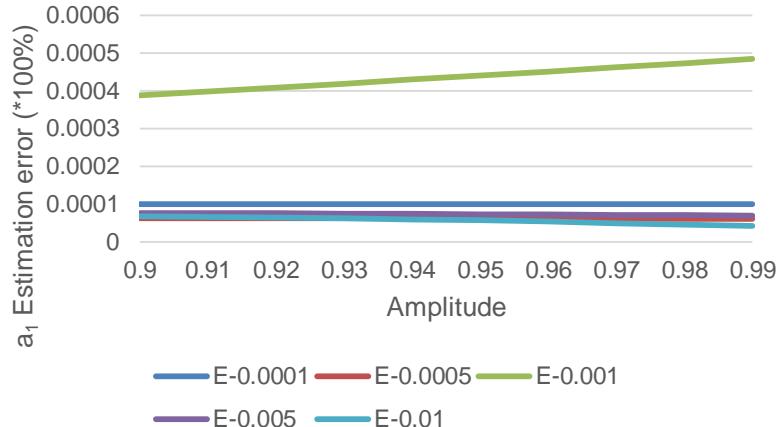
Sampling:18Bit

A : 0.9 ~ 1 amplitude increase step : 0.01

The fundamental estimation error of
18Bit

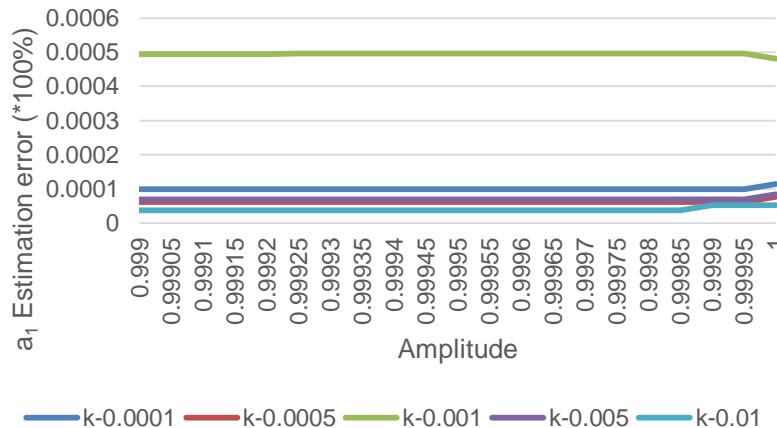


The fundamental estimation error of
18Bit

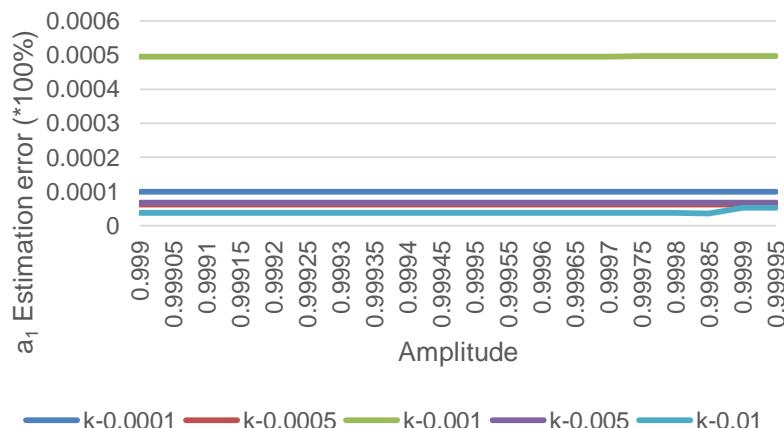


Sampling:18Bit A : 0.999 ~ 1 amplitude increase step : 0.0005

The fundamental estimation error of
18bit



The fundamental estimation error of
18Bit



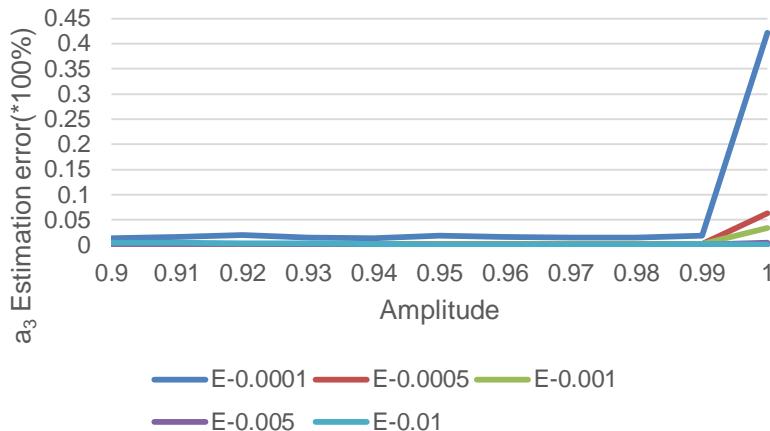
First-order modulator (3rd nonlinearity)

3rd harmonic

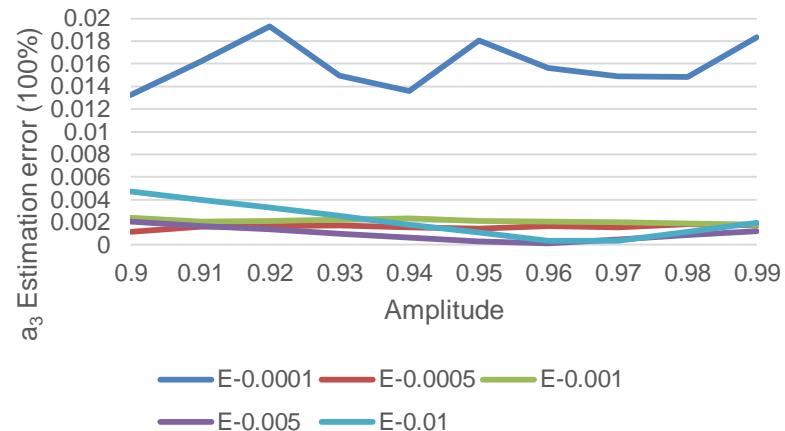
Sampling:18Bit

A : 0.9 ~ 1 amplitude increase step : 0.01

The 3rd harmonics estimation error of 18Bit

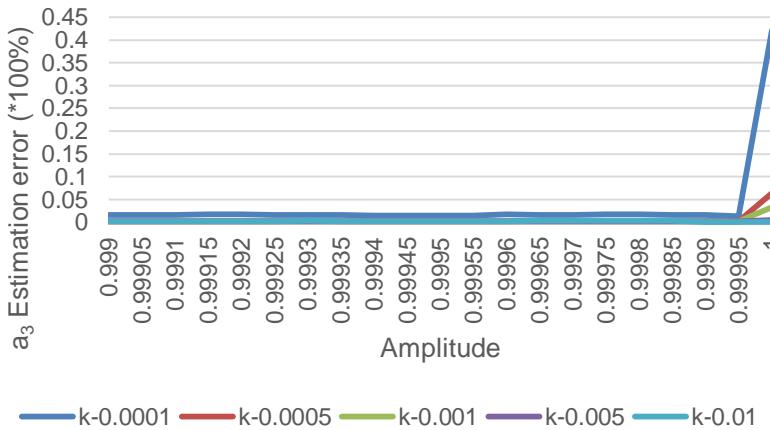


The 3rd harmonics estimation error of 18Bit

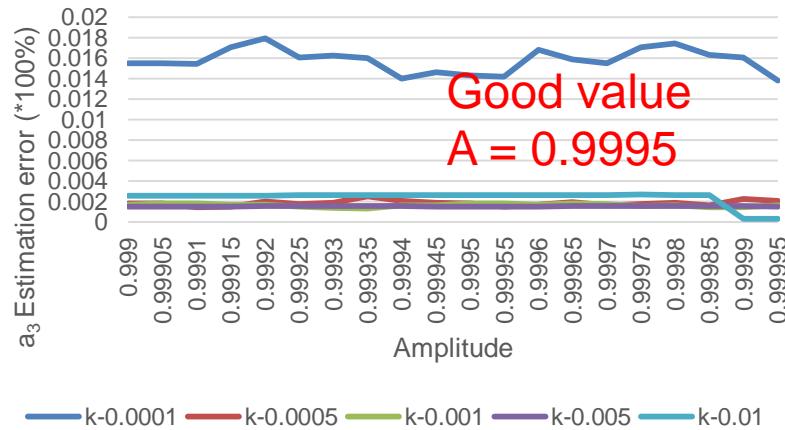


Sampling:18Bit A : 0.999 ~ 1 amplitude increase step : 0.0005

The 3rd harmonic estimation error of 18Bit



The 3rd harmonics estimation error of 18Bit



3rd harmonic

First-order modulator

